

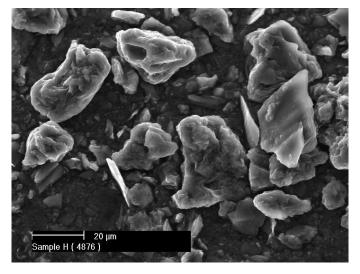
HPPC

July 2023

PRODUCT DESCRIPTION

HPPC provides the following product characteristics

CAS Number (CAS 150339-33-6)	Product ID	HPPC Conductive Black Powder
Appearance: Black Powder Lot # 0413C-1 Microtrac Typical Value Microns (μm) MV 18.65 D10 2.49 D50 11.99 D90 37.15 STD 13.14 Powder Resistivity 0.121 ohm.cm Tube Resistance measured at 200 psig Sheet Resistance 74.10 Ω/□ As measured with a cured, water-based baseline ink formulation at a film thickness of 22.13 μm, 30 wt% Active Soilds Volume Resistivity 74.10 Ω/□/mil As normalized to 1 mil (25 μm) film thickness BET Specific Surface 17.40 m²/g Area Degas, N2 Purge, 300°C, 1 hour Particle Density 2.07 g/ml True Density determination performed on a dried, unground sample Carbon 99.2 wt% Non-Carbon .11 wt% Percent Moisture 0.11 wt% Percent Volatiles 0.41 wt% Percent Sulfur 0.3 wt% Ash Analysis (ICP) Dry Basis XRD Analysis: No Crystalline phase identified via XRD analysis SEM images shown , EDAX available upon request		(CAS 150339-33-6) *A4 Not Classifiable as a human carcinoger
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Tube Resistance measured at 200 psig Sheet Resistance 74.10 Ω/□ As measured with a cured, water-based baseline ink formulation at a film thickness of 22.13 μm, 30 wt% Active Soilds Volume Resistivity 74.10 Ω/□/mil As normalized to 1 mil (25 μm) film thickness BET Specific Surface 17.40 m²/g Area Degas, N2 Purge, 300°C, 1 hour Particle Density 2.07 g/ml True Density determination performed on a dried, unground sample Carbon 99.2 wt% Non-Carbon .11 wt% Components Percent Moisture 0.11 wt% Percent Sulfur 0.3 wt% Ash Analysis (ICP) Dry Basis XRD Analysis: No Crystalline phase identified via XRD analysis SEM images shown , EDAX available upon request	MV D10 D50 D90	18.65 2.49 11.99 37.15
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Area Degas, N2 Purge, 300°C, 1 hour Particle Density 2.07 g/ml True Density determination performed on a dried, unground sample Carbon 99.2 wt% Non-Carbon .11 wt% Components Percent Moisture 0.11 wt% Percent Volatiles 0.41 wt% Percent Sulfur 0.3 wt% Ash Analysis (ICP) Dry Basis XRD Analysis: No Crystalline phase identified via XRD analysis SEM images shown , EDAX available upon request		
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Components Percent Moisture 0.11 wt% Percent Volatiles 0.41 wt% Percent Sulfur 0.3 wt% Ash Analysis (ICP) Dry Basis XRD Analysis: No Crystalline phase identified via XRD analysis SEM images shown , EDAX available upon request	Carbon	99.2 wt%
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Percent Sulfur 0.3 wt% Ash Analysis (ICP) Dry Basis XRD Analysis: No Crystalline phase identified via XRD analysis SEM images shown , EDAX available upon request	Percent Moisture	0.11 wt%
Ash Analysis (ICP) Dry Basis XRD Analysis: No Crystalline phase identified via XRD analysis SEM images shown , EDAX available upon request	Percent Volatiles	0.41 wt%
XRD Analysis: No Crystalline phase identified via XRD analysis SEM images shown , EDAX available upon request	Percent Sulfur	0.3 wt%
No Crystalline phase identified via XRD analysis SEM images shown , EDAX available upon request		
	Ash Analysis (ICP)	Dry Basis
Product Availability 1 metric ton quantities	XRD Analysis:	
	XRD Analysis: No Crys	talline phase identified via XRD analysis



GENERAL INFORMATION

For safe handling information on this product consult the Safety Data Sheet.

STORAGE INFORMATION

Keep container/package tightly closed in a cool, well-ventilated place. Keep at temperatures above freezing. Allowing freezing conditions may degrade product. Store in accordance with local, regional, national, and/or international regulations.

Material removed from containers may be contaminated during use. Do not return product to the original container. Minus 100 will not assume responsibility for product which has been stored or contaminated or stored under conditions other than those previously indicated.